
200V 300W 45MHz

RF POWER MOSFETs

N-CHANNEL ENHANCEMENT MODE

The ARF466FL is a rugged high voltage RF power transistor designed for scientific, commercial, medical and industrial RF power amplifier applications up to 45 MHz. It has been optimized for both linear and high efficiency classes of operation.

- Specified 150 Volt, 40.68 MHz Characteristics:

Output Power = 300 Watts.

Gain = 16dB (Class AB)

Efficiency = 75% (Class C)

- Low Cost Flangeless RF Package.
- Low V_{th} thermal coefficient.
- Low Thermal Resistance.
- Optimized SOA for Superior Ruggedness.

Maximum Ratings

All Ratings: $T_c = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Ratings	Unit
V_{DSS}	Drain-Source Voltage	1000	V
V_{DGO}	Drain-Gate Voltage	1000	
I_D	Continuous Drain Current @ $T_c = 25^\circ\text{C}$	13	A
V_{GS}	Gate-Source Voltage	± 30	V
P_D	Total Power Dissipation @ $T_c = 25^\circ\text{C}$	1153	W
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to 175	$^\circ\text{C}$
T_L	Lead Temperature: 0.063" from Case for 10 Sec.	300	

Static Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Unit
BV_{DSS}	Drain-Source Breakdown Voltage ($V_{GS} = 0\text{V}$, $I_D = 250 \mu\text{A}$)	1000			V
$R_{DS(ON)}$	Drain-Source On-State Resistance ¹ ($V_{GS} = 10\text{V}$ $I_D = 6.5\text{A}$)			1.0	ohms
I_{DSS}	Zero Gate Voltage Drain Current ($V_{DS} = 1000\text{V}$, $V_{GS} = 0\text{V}$)			25	μA
	Zero Gate Voltage Drain Current ($V_{DS} = 800\text{V}$, $V_{GS} = 0\text{V}$, $T_c = 125^\circ\text{C}$)			250	
I_{GSS}	Gate-Source Leakage Current ($V_{DS} = \pm 30\text{V}$, $V_{GS} = 0\text{V}$)			± 100	nA
g_{fs}	Forward Transconductance ($V_{DS} = 25\text{V}$, $I_D = 6.5\text{A}$)	3.3	7	9	mhos
$V_{GS(TH)}$	Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 1\text{mA}$)	2		4	Volts

Thermal Characteristics

Symbol	Parameter	Min	Typ	Max	Unit
R_{eJC}	Junction to Case			0.13	$^\circ\text{C}/\text{W}$
R_{eJHS}	Junction to Sink (High Efficiency Thermal Joint Compound and Planar Heat Sink Surface.)			0.27	

 CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

DYNAMIC CHARACTERISTICS

ARF466FL(G)

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C_{iss}	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 150V$ $f = 1\text{ MHz}$		2000		pF
C_{oss}	Output Capacitance			165		
C_{rss}	Reverse Transfer Capacitance			75		
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = 15V$ $V_{DD} = 500\text{ V}$ $I_D = 13A @ 25^\circ C$ $R_G = 1.6W$		12		ns
t_r	Rise Time			10		
$t_{d(off)}$	Turn-off Delay Time			43		
t_f	Fall Time			10		

FUNCTIONAL CHARACTERISTICS

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
G_{PS}	Common Source Amplifier Power Gain	$f = 40.68\text{ MHz}$	14	16		dB
h	Drain Efficiency	$V_{GS} = 2.5V$ $V_{DD} = 150V$	70	75		%
y	Electrical Ruggedness VSWR 10:1	$P_{out} = 300W$	No Degradation in Output Power			

① Pulse Test: Pulse width < 380μS, Duty Cycle < 2%

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

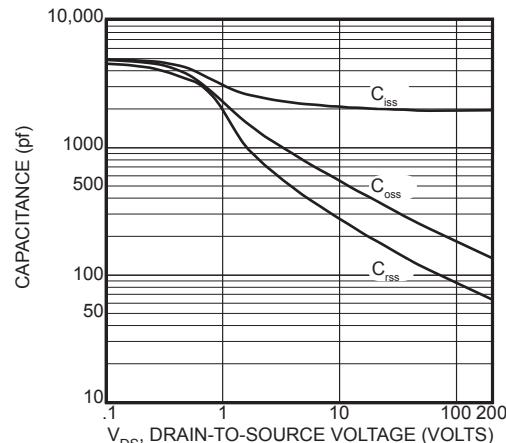


Figure 2, Typical Capacitance vs. Drain-to-Source Voltage

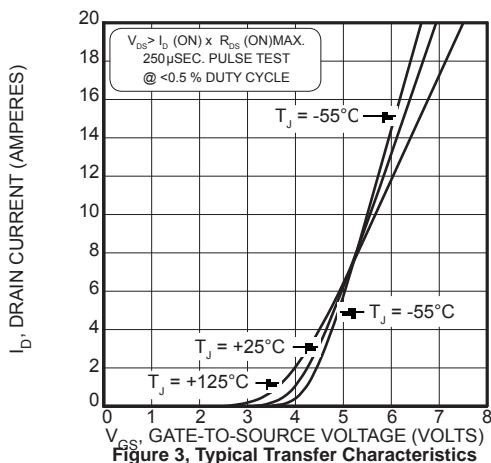


Figure 3, Typical Transfer Characteristics

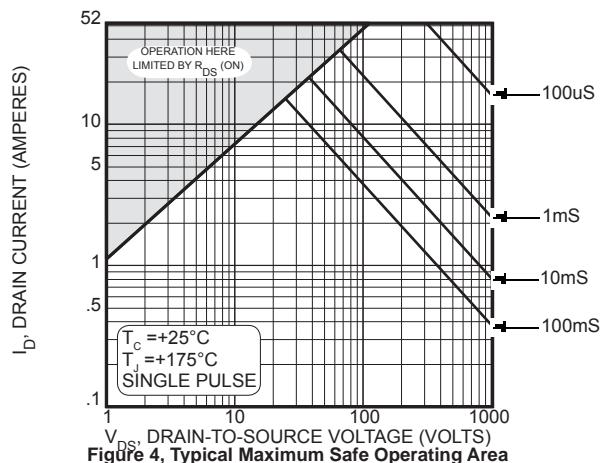


Figure 4, Typical Maximum Safe Operating Area

TYPICAL PERFORMANCE CURVES

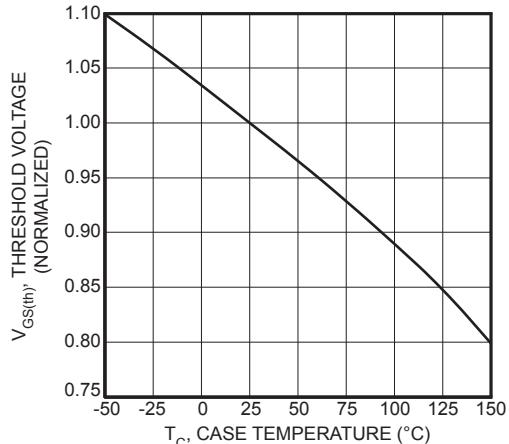


Figure 5, Typical Threshold Voltage vs Temperature

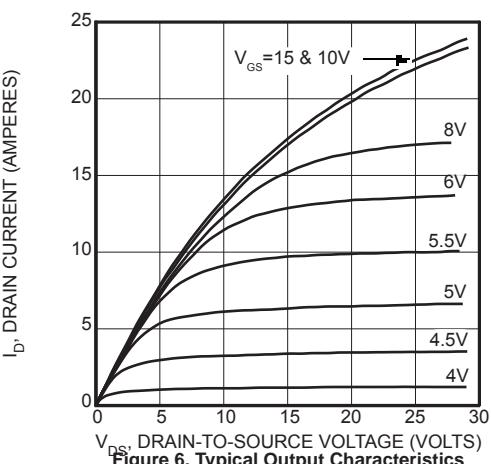


Figure 6, Typical Output Characteristics

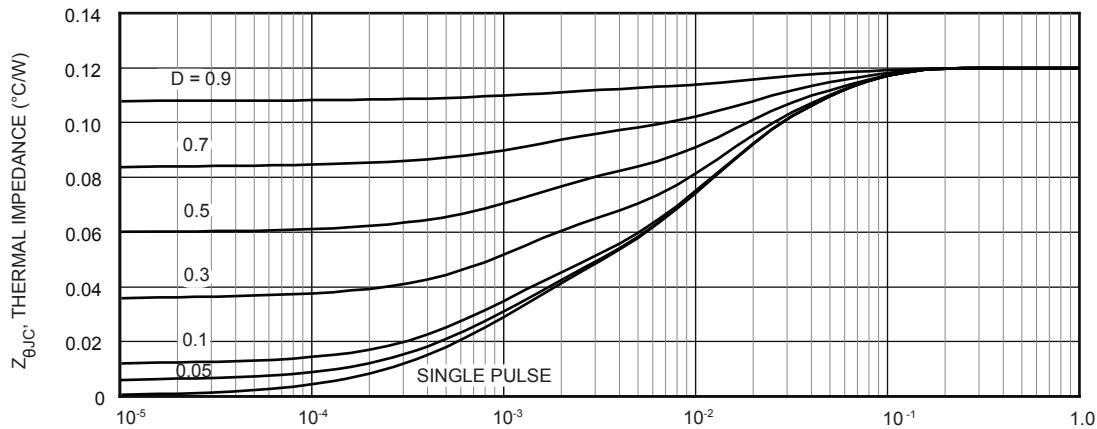


FIGURE 7a, MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs PULSE DURATION

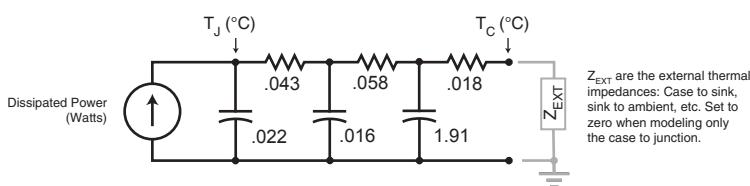


Figure 7b, TRANSIENT THERMAL IMPEDANCE MODEL

Table 1 - Typical Class AB Large Signal Input - Output Impedance

Freq. (MHz)	Z _{IN} (Ω)	Z _{OL} (Ω)
2.0	18 - j 11	30 - j 1.7
13.5	1.3 - j 5	25.7 - j 9.8
27.1	.40 - j 2.6	18 - j 13.3
40.7	.20 - j 1.6	12 - j 12.6
65	.11 + j 0.6	6.2 - j 8.9

Z_{in} - Gate shunted with 25Ω

Z_{OL} - Conjugate of optimum load for 300 W output at V_{dd} = 150V

I_{DQ} = 100mA